

**Search Notes**

Application/Control No.

10/526,492

Examiner

Richard Chan

Applicant(s)/Patent under  
Reexamination

EDER ET AL.

Art Unit

2618

**SEARCHED**

Class	Subclass	Date	Examiner
381	317	9/7/2006	RC
381	312	9/7/2006	RC
455	130	9/7/2006	RC
455	227	9/7/2006	RC
375	316	9/7/2006	RC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR